

Notice of References Cited	Application/Control No. 10/777,918		Applicant(s)/Patent Under Reexamination D'HERS ET AL.	
	Examiner SCOTT L. JARRETT		Art Unit 3624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,282,544	08-2001	Tse et al.	707/101
*	C	US-6,732,115	05-2004	Shah et al.	707/102
*	D	US-6,385,604	05-2002	Bakalash et al.	707/3
*	E	US-7,139,766	11-2006	Thomson et al.	707/101
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*	V	Netz, Amir, OLAP Services: Semiadditive Measures and Inventory Snapshots Microsoft Corporation MSDN, April 1, 1999
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.